**DERWENT-ACC-NO:** 

2004-200161

**DERWENT-WEEK:** 

200435

COPYRIGHT 2004 DERWENT INFORMATION LTD

TITLE:

Process with improved etching rate ratio of nitride

layer to oxide layer and application thereof - for

reducing a loss of the gate oxide layer in the process of

forming a space wall

INVENTOR: CHUN, K; LAY, C

PATENT-ASSIGNEE: NAN YA TECHNOLOGY CORP[NANYN]

PRIORITY-DATA: 2002TW-0105783 (March 25, 2002)

PATENT-FAMILY:

PUB-NO TW 544815 A PUB-DATE

**LANGUAGE** 

**PAGES** MAIN-IPC

N/A 000

August 1, 2003

H01L 021/465

APPLICATION-DATA:

PUB-NO TW 544815A APPL-DESCRIPTOR N/A

APPL-NO 2002TW-0105783

APPL-DATE March 25, 2002

INT-CL (IPC): H01L021/465

ABSTRACTED-PUB-NO: TW 544815A

**BASIC-ABSTRACT**:

NOVELTY - A process with an improved etching rate ratio of nitride layer to oxide layer comprises: providing an etching treatment chamber and a substrate; mounting the substrate in an etching treatment chamber; providing a mixture gas of O2, N2 and CF4; applying a pressure of 30 to 200 Pa and a power of 100 to 1000W on the mixture gas to etch the substrate.

DETAILED DESCRIPTION - A process with an improved etching rate ratio of nitride layer to oxide layer comprises: providing an etching treatment chamber and a substrate; mounting the substrate in an etching treatment chamber, in which the substrate is formed with a nitride layer; providing a mixture gas of O2, N2 and CF4; in which the composition of the mixture gas is O2:N2:CF4=4-50:0-10:1; applying a pressure of 30 to 200 Pa and a power of 100 to 1000W on the mixture gas to etch the substrate.

CHOSEN-DRAWING: Dwg.1/1

TITLE-TERMS: PROCESS IMPROVE ETCH RATE RATIO NITRIDE LAYER OXIDE LAYER APPLY

REDUCE LOSS GATE OXIDE LAYER PROCESS FORMING SPACE WALL

**DERWENT-CLASS: L03 U11** 

CPI-CODES: L04-C07;

EPI-CODES: U11-C05B9B; U11-C07A1; U11-C07C3;

SECONDARY-ACC-NO:

CPI Secondary Accession Numbers: C2004-079207 Non-CPI Secondary Accession Numbers: N2004-158795